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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 7

Complete if Known

Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

Examiner Initials *	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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First Named Inventor	Edward Raymond Dowski, Jr.
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Examiner Name	Unknown JACK DIAZ
Attorney Docket Number	402801

U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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First Named Inventor	Edward Raymond Dowski, Jr.
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JD	1	EPO	0759573 A2		Eastman Kodak Company	02-28-1997		
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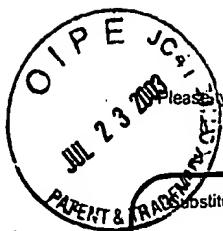
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Sheet 4 of 7

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Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Sheet 5 of 7

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Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
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OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cita No. 1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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		Application Number	09/942,392
		Filing Date	31 August 2001
		First Named Inventor	Edward Raymond Dowski, Jr.
		Group Art Unit	2873
		Examiner Name	Unknown JACK DINH
Sheet	7 of 7	Attorney Docket Number	402801

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	48	Abstract of JP 60247611 A, published 12 July 1985 (Toshiba KK), Patent Abstracts of Japan, 6 May 1986, vol. 010, no. 119 (p-435), 1 page	
	49	POON, TING-CHUNG and MOTAMEDI, MASOUD, "Optical/digital incoherent image processing for extended depth of field", Applied Optics Vol. 26, no. 21, 1 November 1987, pp. 4612-4615	
	50	BRADBURN, SARAH, CATHEY, WADE THOMAS and DOWSKI, EDWARD R., JR., "Realizations of focus invariance in optical-digital systems with wave-front coding", Applied Optics Vol. 36, no. 35, 10 December 1997, pp. 9157-9166	
	51	VAN DER GRACHT, JOSEPH, DOWSKI, EDWARD R., JR., CATHEY, W. THOMAS and BOWEN, JOHN P., "Aspheric optical elements for extended depth of field imaging", SPIE Vol. 2537, pp. 279-288, 1995	
	52	SIEBERT, J. (Officer), International Search Report received in PCT/US01/26126, international filing date 08-02-2001, report completed 06-24-2003, 3 pages	

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Examiner Signature		Date Considered	09/06/04
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